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Fluorescence Spectroscopy

SCIENTISTS interested in fluorescence spectroscopy have been asked to attend a meeting for the purpose of organizing a task group to consider the need for standardization of nomenclature, presentation of spectra, methods of analysis by fluorescence, and an indexing system for reference data. The meeting has been called by Committee E-13 on Absorption Spectroscopy of the American Society for Testing Materials; it will be held June 13 at 8:00 PM in Room 110 of the Physics Building, Ohio State University, Columbus, Ohio, during the Ohio State Molecular Structure Symposium. For further information, contact M. V. Otis, Research Laboratories, Tennessee Eastman Co., Kingsport, Tenn.

Carbon Conference

THE Third Conference on Carbon, cosponsored by the University of Buffalo, the National Science Foundation, and the US Office of Naval Research, will be held in Buffalo, N. Y., June 17–21. Electronic properties of carbons will be treated in the first two days; the following two days will be spent on compounds, reactions, effects of irradiation, and heat-treatment; and the last day will include discussions on processing of carbons and on their high-temperature properties. There will be a total of 80 papers presented, 32 of them by speakers from overseas. The papers presented will be published sometime after the conference in the second volume of the *Proceedings of the Conferences on Carbon*. For further information write to Carbon Conference, University of Buffalo, Buffalo 14, N. Y.

Science, Industry, and Education

A ONE-DAY symposium on science, industry, and education will be presented in Oklahoma City on June 17, 1957, by the Frontiers of Science Foundation of Oklahoma, Inc., in cooperation with the American Institute of Physics and the National Science Foundation. Speakers will include Hakan Sterky, director general and chief of the Royal Swedish Telecommunications Board, Stockholm, Sweden; Lee DuBridge, president of California Institute of Technology; Guy Suits, vice president and director of research, General Electric Company; W. O. Baker, vice president of Bell Telephone Laboratories; H. B. G. Casimir, director of the Laboratory of Physics, N. V. Philips, Eindhoven, The Netherlands; Augustus B. Kinzel, vice president in